Sample Cleaner for Electron Microscopes ZONE II for SEM

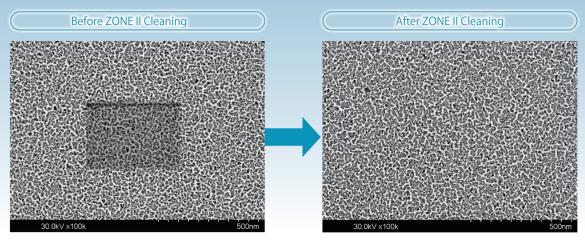


The innovative Zone II Desktop Sample Cleaner uses UV-based cleaning technology to minimize or eliminate hydrocarbon contamination for electron microscopy imaging.



ZONE II for SEM

Ultraviolet Source Hydrocarbon Removal System for SEM Sample Cleaning



Specifications

ltem	Specification
Model No.	ZNE-2000
UV Lamp	Wavelength: 185 nm, 254 nm (20 W, 1000 hr rating)
Specimen Size	100 mm (φ) x 37 mm (H)
Process Mode	UV Cleaning Mode Vacuum Storage Mode
Vacuum Settings	~100 to 500 Torr (100 steps)
Process Setting Time	1 min. to approx. 24 hrs.
Vacuum Pump	Dry vacuum exhaust system
Ozone Exclusion	Built-in Ozone Scrubber
Dimensions	300 mm (W) \times 262 mm (D) \times 326 mm (H)
Weight	Approx.18 kg
Option	Sample Height Adjusting Spacers (7 mm and 9 mm)

Installation Requirements

•	
ltem	Specification
Ambient Temperature	15~30℃
Ambient Humidity	~70% RH (no dew condensation)
Power Requirements	Power supply: AC 100-240 V, 50/60 Hz
	Power consumption: 0.14 kVA
	Plug type: 3-prong
Table Load Resistance	Over 100 kg
Floor Space	650 mm x 650 mm (200 mm from the wall)
Standards	CE marking
	- IEC61010-1 Edition3.0
	- EN61000-6-2 :2005
	- EN61000-6-4: 2007+A1:2011
	- RoHS

System Features

- 1. Safe, non-destructive UV cleaning technology
- 2. Ergonomic form factor with LCD Touch Screen controller
- 3. Transparent sample compartment with motorized door
- 4. Typical sample cleaning time, 5-15 minutes
- 5. Programmable cleaning recipes
- 6. Lab-friendly footprint

Notice: For correct operation, follow the instruction manual when using the instrument. Specifications in this catalog are subject to change with or without notice, as Hitachi High-Technologies Corporation continues to develop the latest technologies and products for

Copyright © Hitachi High-Technologies Corporation 2017. All rights reserved.



http://www.hitachi-hightech.com/global/em/ 24-14, Nishi-shimbashi, 1-chome, Minato-ku Tokyo, 105-8717, Japan Manufactured by:

